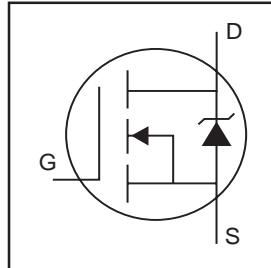


International **IR** Rectifier

PD - 95062A

IRLR2705PbF **IRLU2705PbF**

HEXFET® Power MOSFET



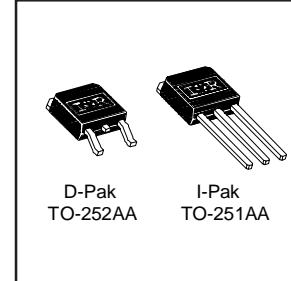
$V_{DSS} = 55V$
 $R_{DS(on)} = 0.040\Omega$
 $I_D = 28A^{(5)}$

- Logic-Level Gate Drive
- Ultra Low On-Resistance
- Surface Mount (IRLR2705)
- Straight Lead (IRLU2705)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The D-PAK is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	28	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	20	
I_{DM}	Pulsed Drain Current ^①	110	
$P_D @ T_C = 25^\circ C$	Power Dissipation	68	W
	Linear Derating Factor	0.45	W/°C
V_{GS}	Gate-to-Source Voltage	± 16	V
E_{AS}	Single Pulse Avalanche Energy ^②	110	mJ
I_{AR}	Avalanche Current ^①	16	A
E_{AR}	Repetitive Avalanche Energy ^①	6.8	mJ
dv/dt	Peak Diode Recovery dv/dt ^③	5.0	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	

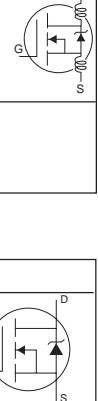
Thermal Resistance

	Parameter	Typ.	Max.	Units
R_{0JC}	Junction-to-Case	—	2.2	°C/W
R_{0JA}	Case-to-Ambient (PCB mount)**	—	50	
R_{0JA}	Junction-to-Ambient	—	110	

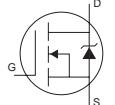
** When mounted on 1" square PCB (FR-4 or G-10 Material) .

For recommended footprint and soldering techniques refer to application note #AN-994

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	55	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.065	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	—	0.040	W	$V_{\text{GS}} = 10\text{V}, I_D = 17\text{A}$ ④
		—	—	0.051		$V_{\text{GS}} = 5.0\text{V}, I_D = 17\text{A}$ ④
		—	—	0.065		$V_{\text{GS}} = 4.0\text{V}, I_D = 14\text{A}$ ④
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	1.0	—	2.0	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	11	—	—	S	$V_{\text{DS}} = 25\text{V}, I_D = 16\text{A}$ ⑦
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	$V_{\text{DS}} = 55\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	250		$V_{\text{DS}} = 44\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 150^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 16\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -16\text{V}$
Q_g	Total Gate Charge	—	—	25	nC	$I_D = 16\text{A}$
Q_{gs}	Gate-to-Source Charge	—	—	5.2		$V_{\text{DS}} = 44\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	14		$V_{\text{GS}} = 5.0\text{V}, \text{See Fig. 6 and 13}$ ④⑦
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	8.9	—	ns	$V_{\text{DD}} = 28\text{V}$
t_r	Rise Time	—	100	—		$I_D = 16\text{A}$
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	21	—		$R_G = 6.5\Omega, V_{\text{GS}} = 5.0\text{V}$
t_f	Fall Time	—	29	—		$R_D = 1.8\Omega, \text{See Fig. 10}$ ④⑦
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact ⑥
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	880	—		$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	220	—	pF	$V_{\text{DS}} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	94	—		$f = 1.0\text{MHz}, \text{See Fig. 5}$ ⑦

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	28	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	110		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 17\text{A}, V_{\text{GS}} = 0\text{V}$ ④
t_{rr}	Reverse Recovery Time	—	76	110	ns	$T_J = 25^\circ\text{C}, I_F = 16\text{A}$
Q_{rr}	Reverse Recovery Charge	—	190	290	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ④⑦
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② $V_{\text{DD}} = 25\text{V}$, starting $T_J = 25^\circ\text{C}$, $L = 610\mu\text{H}$
 $R_G = 25\Omega, I_{AS} = 16\text{A}$. (See Figure 12)
- ③ $I_{SD} \leq 16\text{A}$, $dI/dt \leq 270\text{A}/\mu\text{s}$, $V_{\text{DD}} \leq V_{(\text{BR})\text{DSS}}$,
 $T_J \leq 175^\circ\text{C}$
- ④ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.

- ⑤ Calculated continuous current based on maximum allowable junction temperature; Package limitation current = 20A.
- ⑥ This is applied for I-PAK, L_S of D-PAK is measured between lead and center of die contact.
- ⑦ Uses IRLZ34N data and test conditions.

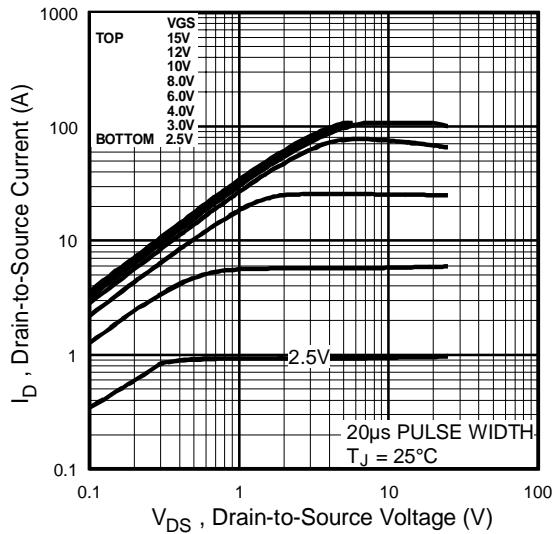


Fig 1. Typical Output Characteristics

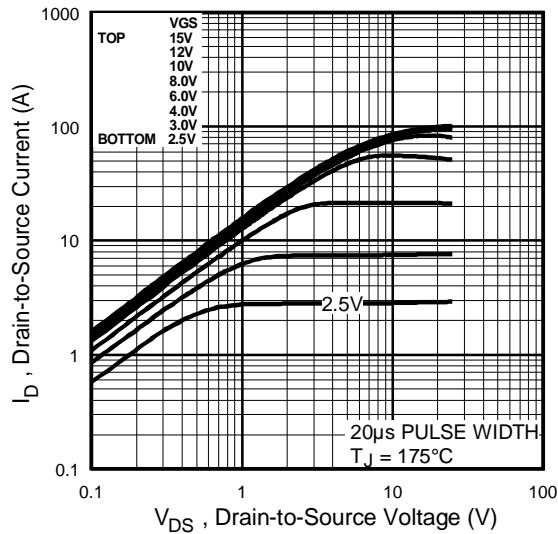


Fig 2. Typical Output Characteristics

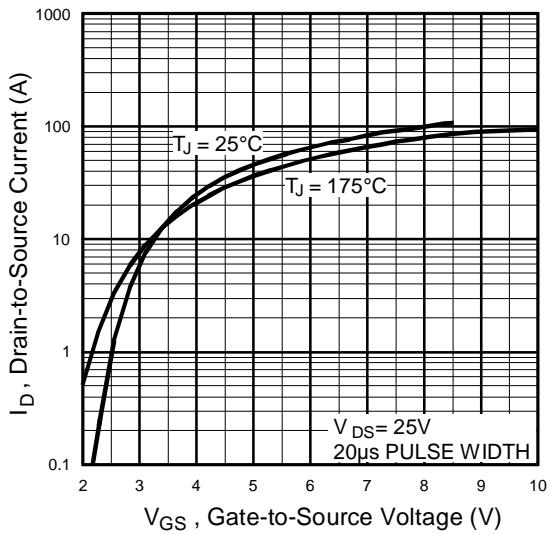


Fig 3. Typical Transfer Characteristics

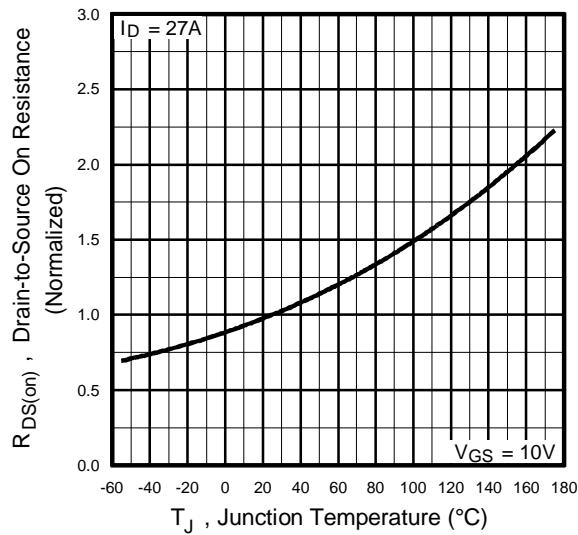


Fig 4. Normalized On-Resistance
Vs. Temperature

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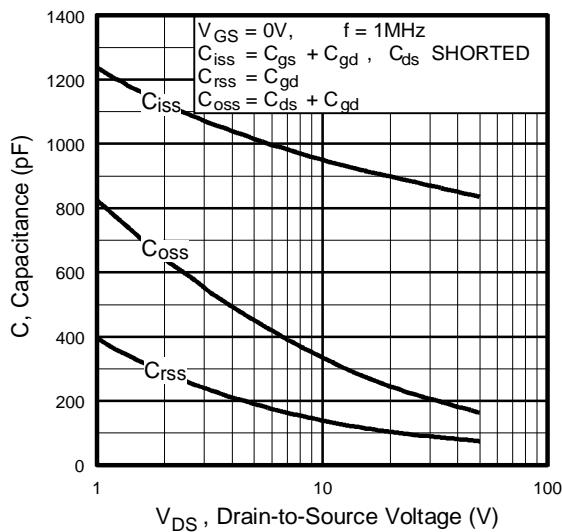


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

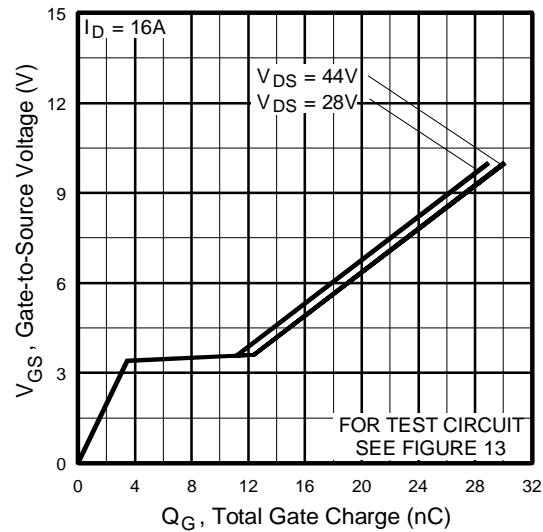


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

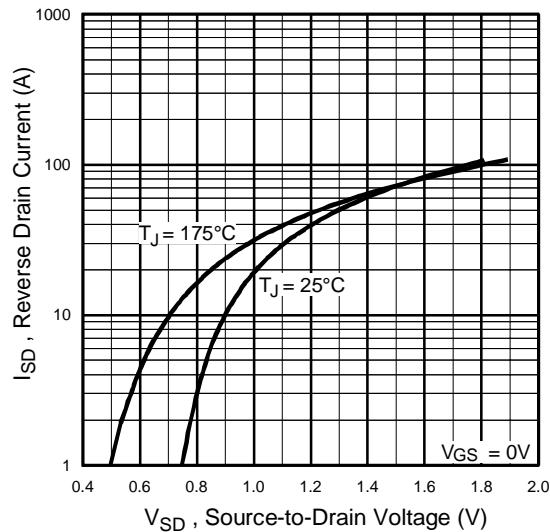


Fig 7. Typical Source-Drain Diode
Forward Voltage

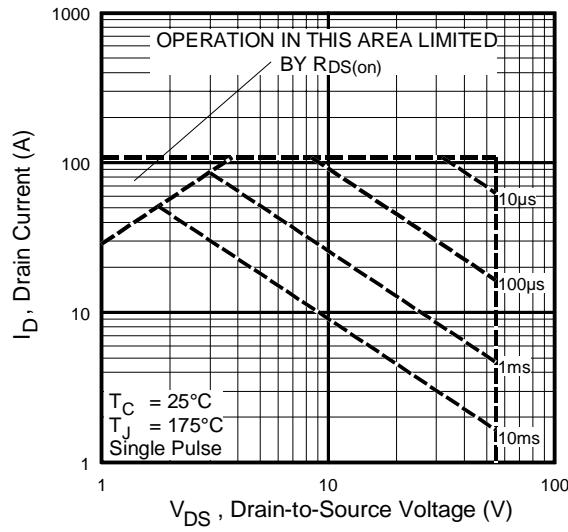


Fig 8. Maximum Safe Operating Area

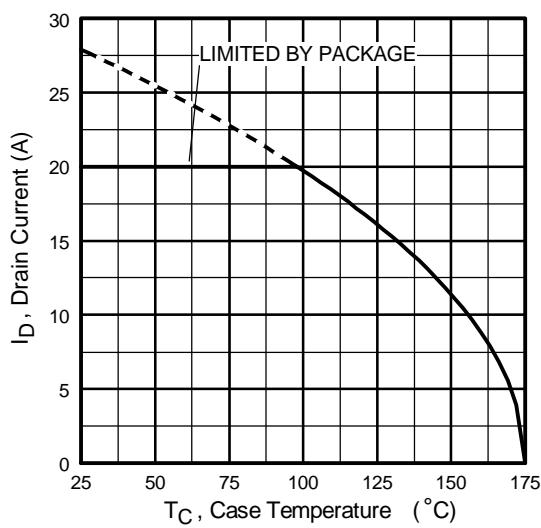


Fig 9. Maximum Drain Current Vs.
Case Temperature

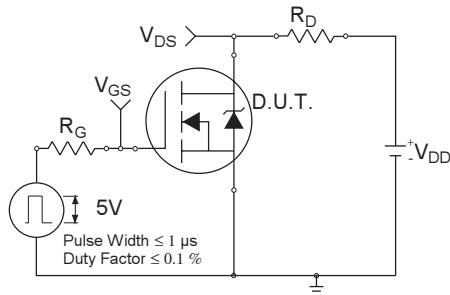


Fig 10a. Switching Time Test Circuit

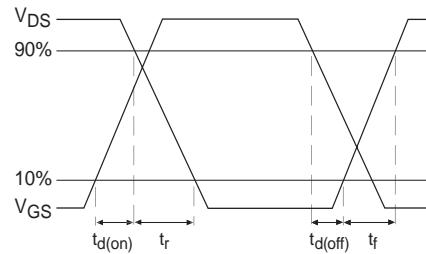


Fig 10b. Switching Time Waveforms

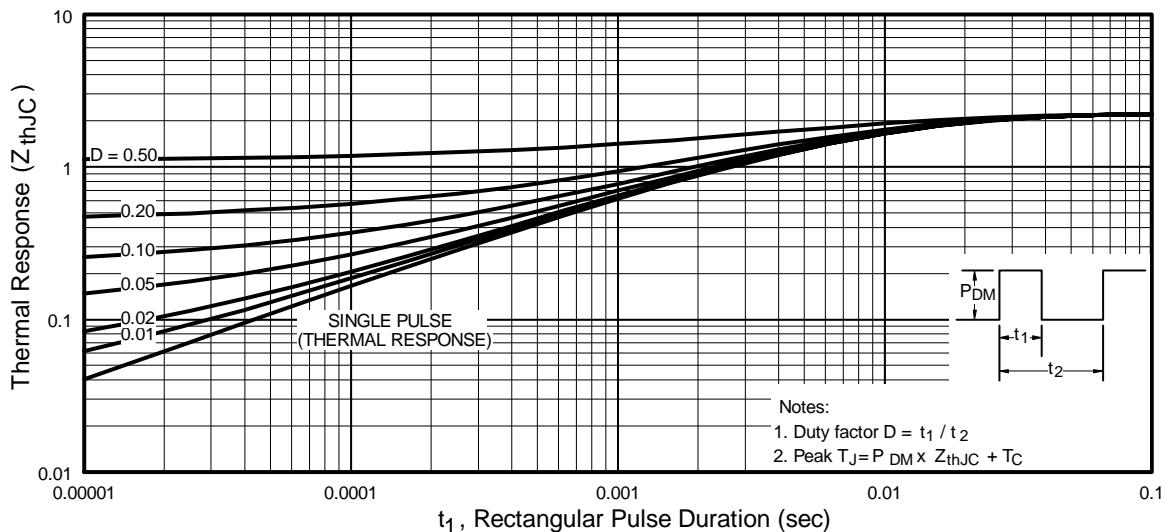


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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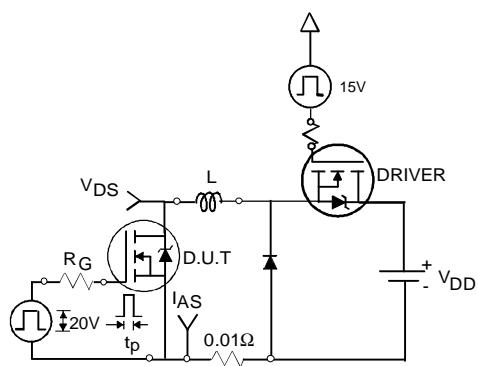


Fig 12a. Unclamped Inductive Test Circuit

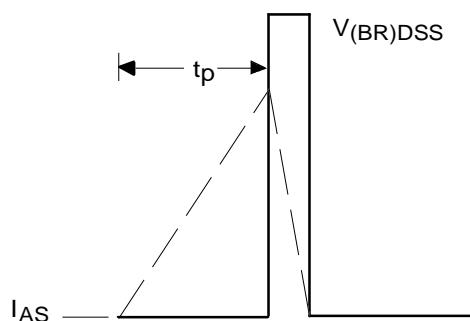
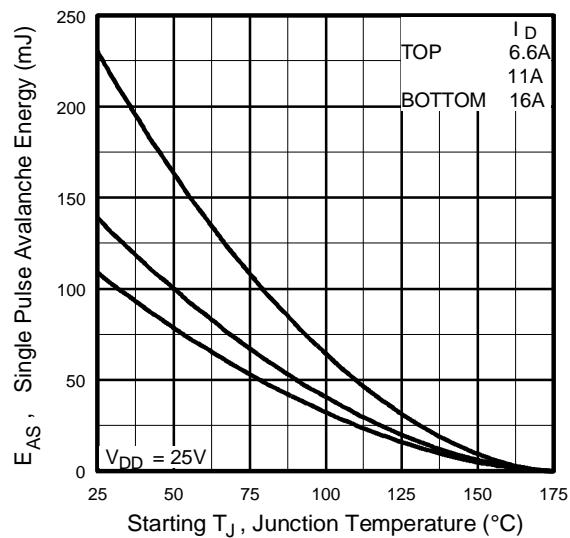


Fig 12b. Unclamped Inductive Waveforms

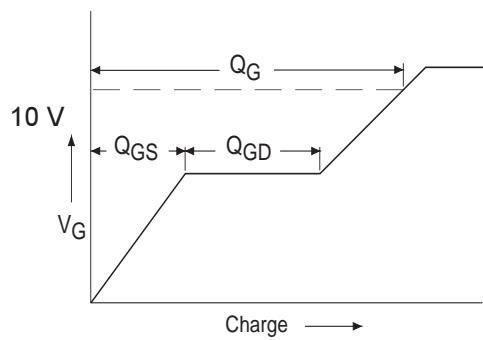


Fig 13a. Basic Gate Charge Waveform

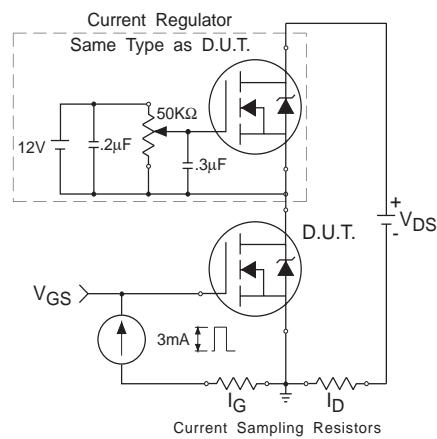
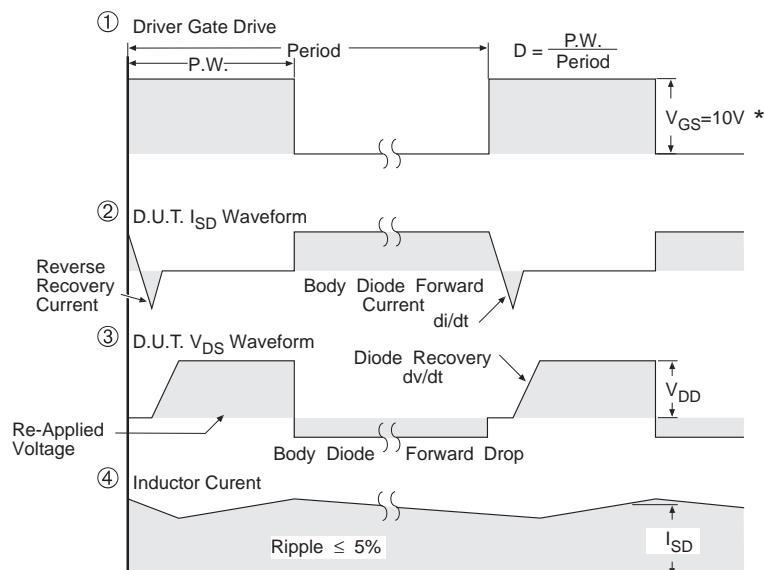
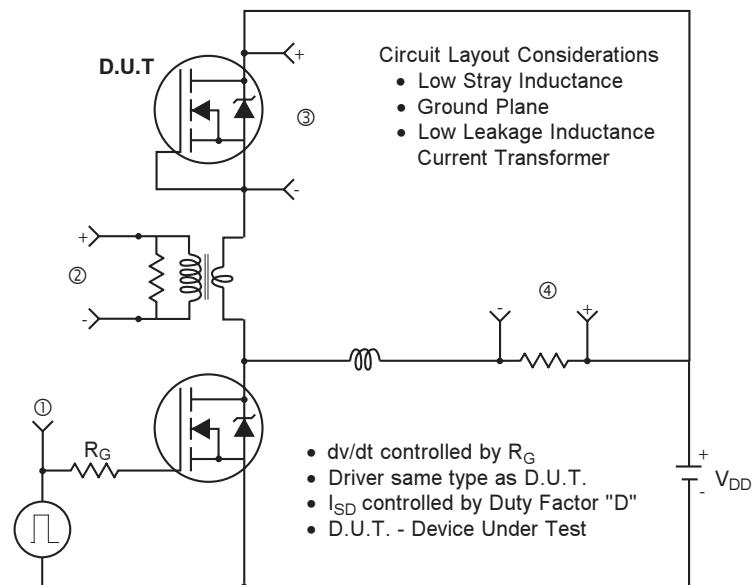


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* $V_{GS} = 5V$ for Logic Level Devices

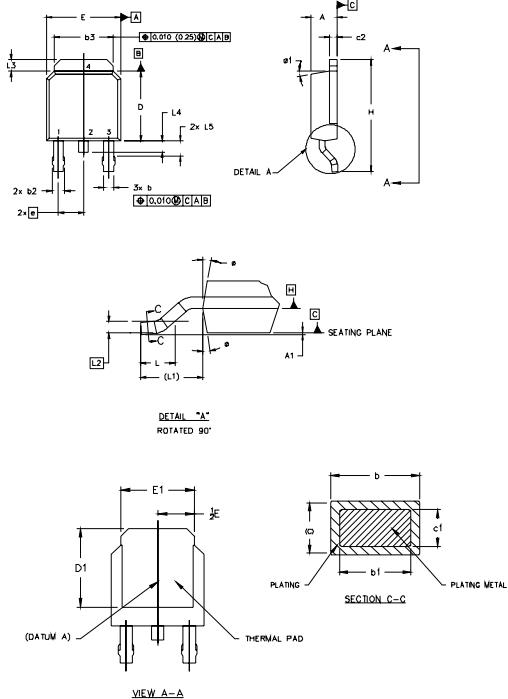
Fig 14. For N-Channel HEXFETs

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D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)



NOTES:					
1.0 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994. 2.0 DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS]. 3.0 LEAD DIMENSION UNCONTROLLED IN LS. 4.0 DIMENSION D1 AND E1 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD. 5.0 SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 [0.127] AND .010 [0.254] FROM THE LEAD TIE BAR. 6.0 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY. 7.0 OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.					
SYMBOL	DIMENSIONS		NOTES		
	MILLIMETERS	INCHES			
A	2.18	.239	.086	.094	
A1	.15	.059	.005	.005	
b	.64	.089	.026	.035	5
b1	.64	.079	.026	.031	5
b2	.76	.114	.030	.045	
b3	.495	.546	.195	.215	
c	.46	.61	.018	.024	5
c1	.41	.56	.016	.022	5
c2	.046	.089	.016	.035	5
D	.597	.622	.235	.245	6
D1	.521	—	.205	—	4
E	.635	.673	.250	.265	6
E1	4.32	—	.170	—	4
e	2.29	—	.090	.090	
H	3.40	10.41	.370	.410	
L	1.40	1.78	.055	.070	
L1	2.74	REF	.108	REF	
L2	.0051	.056	.020	.056	
L3	.089	1.27	.035	.050	
L4	—	1.02	—	.040	
L5	1.14	1.52	.045	.060	
•	0°	10°	0°	10°	
•1	0°	15°	0°	15°	

LEAD ASSIGNMENTS

HEXFET

- 1. - GATE
- 2. - DRAIN
- 3. - SOURCE
- 4. - DRAIN

IGBTs, CoPACK

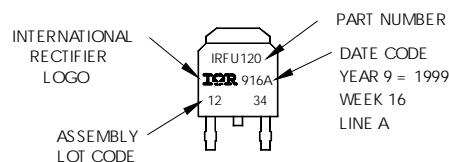
- 1. - GATE
- 2. - COLLECTOR
- 3. - Emitter
- 4. - COLLECTOR

3

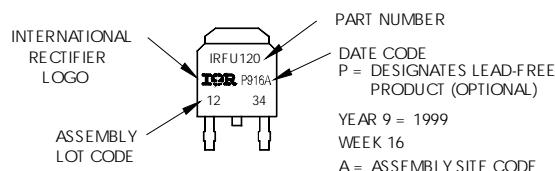
D-Pak (TO-252AA) Part Marking Information

EXAMPLE: THIS IS AN IRFR120
WITH ASSEMBLY
LOT CODE 1234
ASSEMBLED ON WW 16, 1999
IN THE ASSEMBLY LINE "A"

Note: "P" in assembly line position
indicates "Lead-Free"

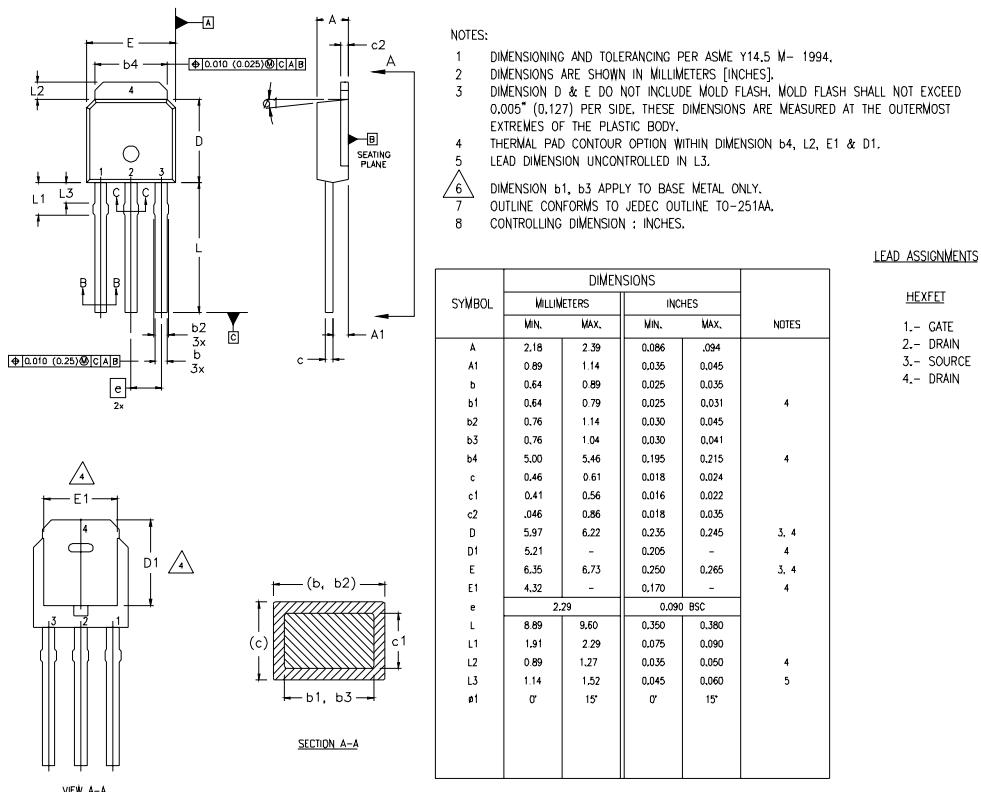


OR



I-Pak (TO-251AA) Package Outline

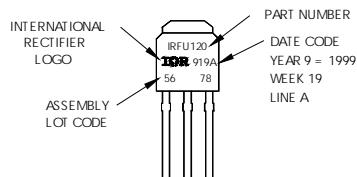
Dimensions are shown in millimeters (inches)



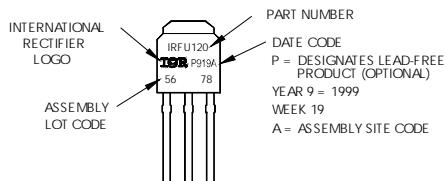
I-Pak (TO-251AA) Part Marking Information

EXAMPLE: THIS IS AN IRFU120
 WITH ASSEMBLY
 LOT CODE 5678
 ASSEMBLED ON WW 19, 1999
 IN THE ASSEMBLY LINE "A"

Note: "P" in assembly line
 position indicates "Lead-Free"



OR

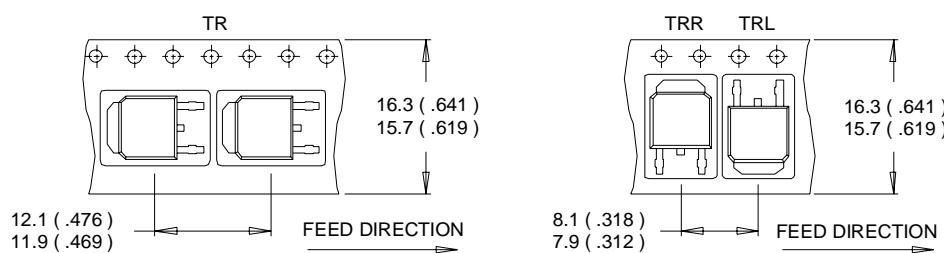


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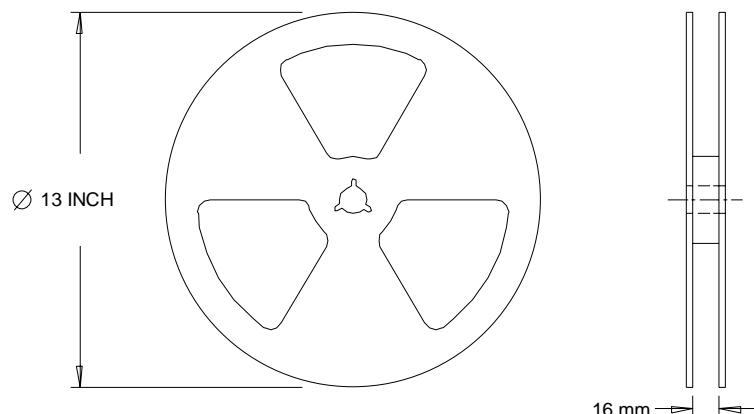
D-Pak (TO-252AA) Tape & Reel Information

Dimensions are shown in millimeters (inches)



NOTES :

1. CONTROLLING DIMENSION : MILLIMETER.
2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :

1. OUTLINE CONFORMS TO EIA-481.

Data and specifications subject to change without notice.

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IR Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105
TAC Fax: (310) 252-7903

Visit us at www.irf.com for sales contact information. 01/05

Note: For the most current drawings please refer to the IR website at:
<http://www.irf.com/package/>